

Modelling Of Variation Trained Drowsy Cache

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ABSTRACT:

On-chip caches represent a sizable fraction of the total power consumption of microprocessors. Although large caches can significantly improve performance, they have the potential to increase power consumption. As feature sizes shrink, the dominant component of this power loss will be leakage. However, during a fixed period of time the activity in a cache is only centered on a small subset of the lines. This behavior can be exploited to cut the leakage power of large caches by putting the cold cache lines into a state preserving, low-power drowsy mode. Moving lines into and out of drowsy state incurs a slight performance loss. In this paper we investigate policies and circuit techniques for implementing drowsy caches. We show that with simple architectural techniques, about 80%-90% of the cache lines can be maintained in a drowsy state without affecting performance by more than 1%. According to our projections, in a 0.07 μ m CMOS process, drowsy caches will be able to reduce the total energy (static and dynamic) consumed in the caches by 50%-75%. We also argue that the use of drowsy caches can simplify the design and control of low leakage caches, and avoid the need to completely turn off selected cache lines and lose their state.

Index Terms— Cache, drowsy cache, static random access memory (SRAM), AXI protocol

I. INTRODUCTION

In this paper, we propose a drowsy cache architecture that is aware of process variability within the structure. By using a simple and low cost distributed supply voltage management unit (one for each cache way) our pro-posed architecture allows a majority of the memory cells to operate at a reduced voltage

The gap between processor and memory speed continues to widen, cache performance becomes increasingly critical to the overall system performance. Researchers have observed that different program regions may have different access patterns and reuse types, and it is possible to fine -tune the cache management mechanism to exploit the reuse behaviors and achieve a better memory performance. cache schemes proposed previously, the cache selection and the bypass decision are made by the hardware.

To use cache mapping to improve program memory performance, we must have a way to estimate the dynamic memory access behavior of the program. Typical applications which run on the Strong ARM and the XScale processors perform multimedia tasks, encryption, and compression, among others

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II. PROPOSED ARCHITECTURE

To counter the effect of process variations, typically designers overdrive the entire memory array. This leads to extra power consumption as both leakage and dynamic power increase. We are proposing to use a modified wordline driver peripheral circuit to allow selective wordline overdriving utilizing a small one step charge pump. The wordline peripheral circuit will drive the wordline in two phases. In the first phase, using the supplied Vdd the wordline is driven to Vdd. In the second phase the charge pump will overdrive the wordline voltage increasing the Vgs above the supply Vdd. Increase in Vgs improves both access and write time to the cell as will be described in the following sections DRV for cold lines which are determined by cache access pattern and are managed via the proposed architecture. Cache ways that are supplied with this voltage are referred to as “Cold Ways”. The remaining two voltage levels are used in cache ways located within the Cache Window of

Execution (CWoE) V_{dd}^{LOW} is supplied if cache way could operate correctly in that voltage, otherwise cache way is supplied with V_{dd}^{HIGH} .

A 6T SRAM memory, however, can be manufactured in a standard logic process and continues to offer high-performance at a reasonable density and power dissipation. SRAMs will likely remain the dominant on-die memory technology, as SRAM cells have already been demonstrated down to the 32nm technology node. A 6T SRAM cell uses a pair of cross-coupled inverters as its bi-stable storage element with two additional NMOS devices for read and write access (Figure 1).

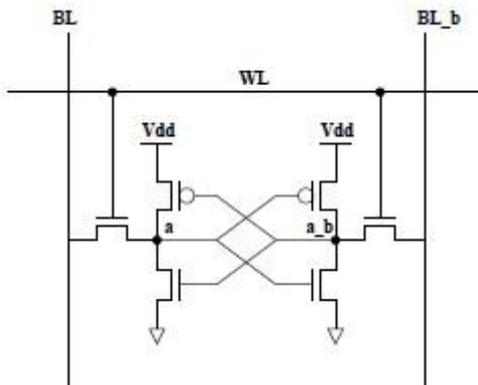


Fig 1. 6T SRAM cell

The cells are aggregated into cell arrays to share the decoding and I/O logic. On a read, the decoder raises the wordline (WL) of the desired word. The bitlines (BL and BL b) have been precharged to a reference voltage, and the cell drives a differential current onto the bitlines according to the stored value. The cell current is relatively weak for the bitline capacitance, so to speed the read operation, a sense amplifier in the I/O logic amplifies the bitline differential voltage to produce a full swing logic value.

Figure 2 & 3 shows how a read transaction uses the read address and read data channels and how a write transaction uses the write address, write data, and write response channels.

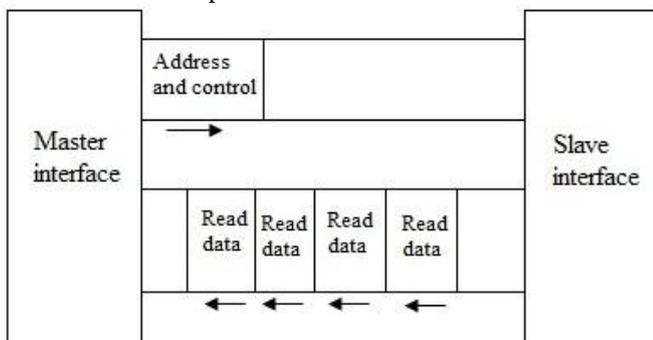


Figure 2. Channel architecture of reads

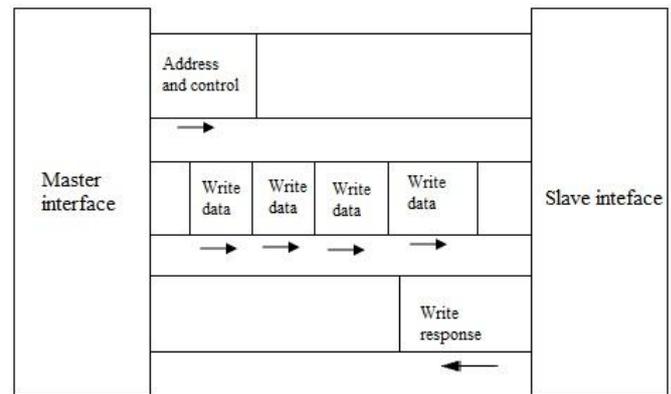


Figure 3. Channel architecture of writes

A. Channel definition:

Each of the five independent channels consists of a set of information signals and uses a two-way VALID and READY handshake mechanism. The information source uses the VALID signal to show when valid data or control information is available on the channel. The destination uses the READY signal to show when it can accept the data. Both the read data channel and the write data channel also include a LAST signal to indicate when the transfer of the final data item within a transaction takes place.

I. Read and write address channels:

Read and write transactions each have their own address channel. The appropriate address channel carries all of the required address and control information for a transaction.

The AXI protocol supports the following mechanisms:

- Variable-length bursts, from 1 to 16 data transfers per burst
- bursts with a transfer size of 8-1024 bits
- Wrapping, incrementing, and non-incrementing bursts
- Atomic operations, using exclusive or locked accesses
- System-level caching and buffering control
- Secure and privileged access.

1. Read data channel:

The read data channel conveys both the read data and any read response information from the slave back to the master. The read data channel includes:

- The data bus, which can be 8, 16, 32, 64, 128, 256, 512, or 1024 bits wide
- A read response indicating the completion status of the read transaction.

2. Write data channel:

The write data channel conveys the write data from the master to the slave and includes:

- The data bus, which can be 8, 16, 32, 64, 128, 256, 512, or 1024 bits wide

- One byte lane strobe for every eight data bits, indicating which bytes of the data bus are valid.

Write data channel information is always treated as buffered, so that the master can perform write transactions without slave acknowledgement of previous write transactions.

B. Basic Transactions:

This section gives examples of basic AXI protocol transactions. Each example shows the VALID and READY handshake mechanism. Transfer of either address information or data occurs when both the VALID and READY signals are HIGH. The examples are provided in:

1. Read burst example:

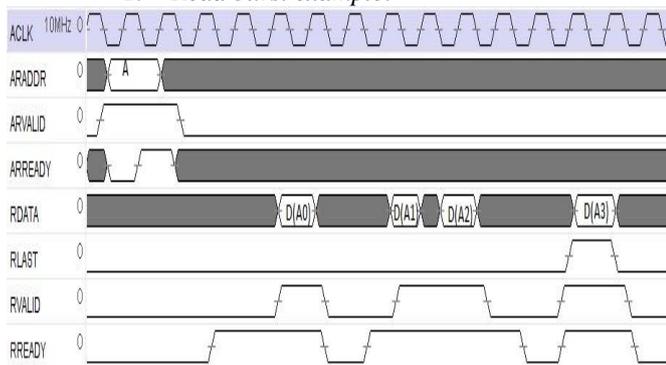


Figure 4. Read burst

Figure 4 shows a read burst of four transfers. In this example, the master drives the address, and the slave accepts it one cycle later.

The master also drives a set of control signals showing the length and type of the burst, but these signals are omitted from the figure for clarity. After the address appears on the address bus, the data transfer occurs on the read data channel. The slave keeps the VALID signal LOW until the read data is available. For the final data transfer of the burst, the slave asserts the RLAST signal to show that the last data item is being transferred.

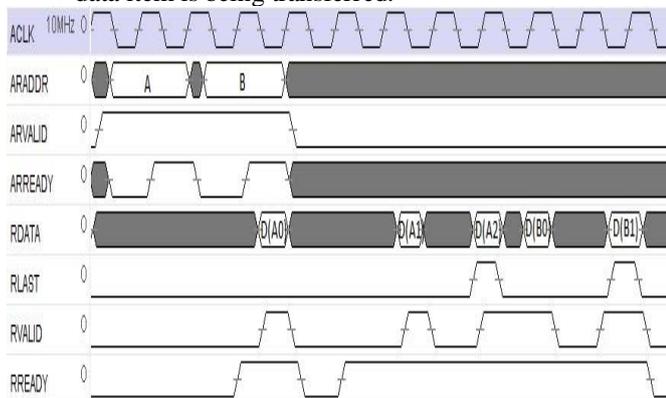


Figure 5. Overlapping read bursts

Figure 5 shows how a master can drive another burst address after the slave accepts the first

address. This enables a slave to begin processing data for the second burst in parallel with the completion of the first burst.

1. Write burst example:

The process starts when the master sends an address and control information on the write address channel. The master then sends each item of write data over the write data channel. When the master sends the last data item, the WLAST signal goes HIGH. When the slave has accepted all the data items, it drives a write response back to the master to indicate that the write transaction is complete. As shown in fig 6.

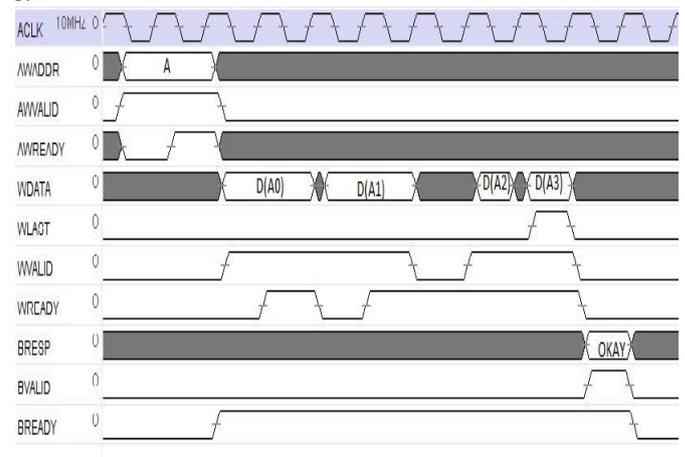


Figure 6. Write burst

III. AXI PROTOCOL

AXI is part of ARM AMBA, a family of micro controller buses first introduced in 1996. The first version of AXI was first included in AMBA 3.0, released in 2003. AMBA 4.0, released in 2010, includes the second version of AXI, AXI4.

There are three types of AXI4 interfaces:

- AXI4—for high-performance memory-mapped requirements.
- AXI4-Lite—for simple, low-throughput memory-mapped communication (for example, to and from control and status registers).
- AXI4-Stream—for high-speed streaming data.

C. AXI4:

The AXI4 protocol is an update to AXI3 which is designed to enhance the performance and utilization of the interconnect when used by multiple masters.

D. AXI4-Lite:

AXI4-Lite is a subset of the AXI4 protocol intended for communication with simpler, smaller control register-style interfaces in components. The AXI4-Lite IP Interface is a part of the Xilinx family of Advanced RISC Machine (ARM) Advanced Microcontroller Bus Architecture (AMBA) Advanced

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